AMENDMENTS TO THE CLAIMS

The claims are not amended. A listing of the claims, including their current status, is set forth below.

1. **(Previously presented)** An ionization chamber for a mass spectrometer ion source, said ionization chamber comprising an inert super alloy.

2. **(Original)** An ionization chamber as recited in claim 1, wherein said inert super alloy is Inconel™ 625.

3. **(Original)** A system for analyzing a sample having constituents, said system comprising an ion source having an ionization chamber with inward facing surfaces defining an interior volume, wherein said interior volume is exposed to said constituents and said ionization chamber comprises a substrate and an inward facing surface layer supported by said substrate, said layer comprising a super alloy.

4. **(Previously presented)** An ionization chamber for a mass spectrometer ion source, said ionization chamber having an inner surface comprising a conductive material selected from the group consisting of Inconel™ 625, Inconel™ 601 and Hastelloy®.

5. **(Original)** An ionization chamber as recited in claim 4, wherein said inner surface has a resistivity lower than 0.001 ohm-cm.

6. **(Original)** An ionization chamber as recited in claim 4, wherein said inner surface is an outer surface of a coating.

7. **(Original)** An ionization chamber as recited in claim 4, additionally comprising a substrate positioned to support said inner surface.

8. **(Previously presented)** An ionization chamber for a mass spectrometer ion source, said ionization chamber having a coated inner surface for reducing interaction

with reactive samples, wherein said coated inner surface comprises an abrasion-resistant Inconel™ 625 material of thickness greater than 0.1 micron.

9. **(Original)** An ionization chamber as recited in claim 8, wherein said thickness is also less than about 10 microns.

10. **(Original)** A system for analyzing a sample having constituents, said system comprising an ion source having an ionization chamber with inward facing surfaces defining an interior volume, wherein said interior volume is exposed to said constituents and said ionization chamber comprises an electrically-conducting substrate and an inward facing surface layer supported by said substrate, said layer including an inert material selected from the group consisting of Inconel™ 625, Inconel™ 601 and Hastelloy®.

11. **(Previously presented)** A method of reducing interaction of a reactive analyte with a surface of a mass spectrometer ion source, comprising applying a coating selected from the group consisting of Inconel™ 625, Inconel™ 601 and Hastelloy® to the surface.

12. **(Cancelled)**

13. **(Previously presented)** An ionization chamber for a mass spectrometer comprising a super alloy.

14. **(Previously presented)** A mass spectrometer comprising:
an ionization chamber comprising a super alloy.

15. **(Previously presented)** An mass spectrometer ionization chamber comprising:
an inert super alloy that provides resistance to abrasion and corrosion and that has low iron content.

16. **(Previously presented)** A mass spectrometer comprising:

an ionization chamber comprising an inert super alloy that provides resistance to abrasion and corrosion and that has low iron content.

17. **(Previously presented)** An mass spectrometer ionization chamber comprising:

at least 58% nickel, 20-23% chromium, 0.1% carbon, 0.5% manganese, 0.5% silicon, no more than 5.0% iron, no more than 0.015% sulfur, no copper, no more than 0.40% aluminum, no more than 0.40% titanium, no more than 0.015% lead, no more than 1% cobalt, 3.15-4.15% niobium, no boron and 8.0-10.0% molybdenum;

58.0-63.0% nickel, 21.0-25.0% chromium, 1.0-1.7% aluminum, less than 0.10% carbon, less than 1.0% manganese, less than 0.015% sulfur, less than 0.50% silicon, less than 1.0% copper and the remaining percent iron; or

0-0.4% aluminum, 0-0.016% boron, 0-0.5% columbium and niobium, 1.5-5.0% cobalt, 16-30% chromium, 0-2% copper, 3-20% iron, 0.5-1.5% manganese, 2.5-16% molybdenum, 43-71% nickel, 0.08-5% silicon, 0.07% or less titanium, 4% or less tungsten and 0.35% or less vanadium.

18. **(Previously presented)** A mass spectrometer comprising:

an ionization chamber comprising:

at least 58% nickel, 20-23% chromium, 0.1% carbon, 0.5% manganese, 0.5% silicon, no more than 5.0% iron, no more than 0.015% sulfur, no copper, no more than 0.40% aluminum, no more than 0.40% titanium, no more than 0.015% lead, no more than 1% cobalt, 3.15-4.15% niobium, no boron and 8.0-10.0% molybdenum;

58.0-63.0% nickel, 21.0-25.0% chromium, 1.0-1.7% aluminum, less than 0.10% carbon, less than 1.0% manganese, less than 0.015% sulfur, less than 0.50% silicon, less than 1.0% copper and the remaining percent iron; or

0-0.4% aluminum, 0-0.016% boron, 0-0.5% columbium and niobium, 1.5-5.0% cobalt, 16-30% chromium, 0-2% copper, 3-20% iron, 0.5-1.5% manganese, 2.5-16% molybdenum, 43-71% nickel, 0.08-5% silicon, 0.07% or less titanium, 4% or less tungsten and 0.35% or less vanadium.

19. **(Previously presented)** An mass spectrometer ionization chamber comprising Inconel™ 625, Inconel™ 601 or Hastelloy®.

20. **(Previously presented)** A mass spectrometer comprising:
an ionization chamber comprising Inconel™ 625, Inconel™ 601 or Hastelloy®.